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BEDIFF et al.
Y0R920030340US1 (DPM)

FIG. 1a

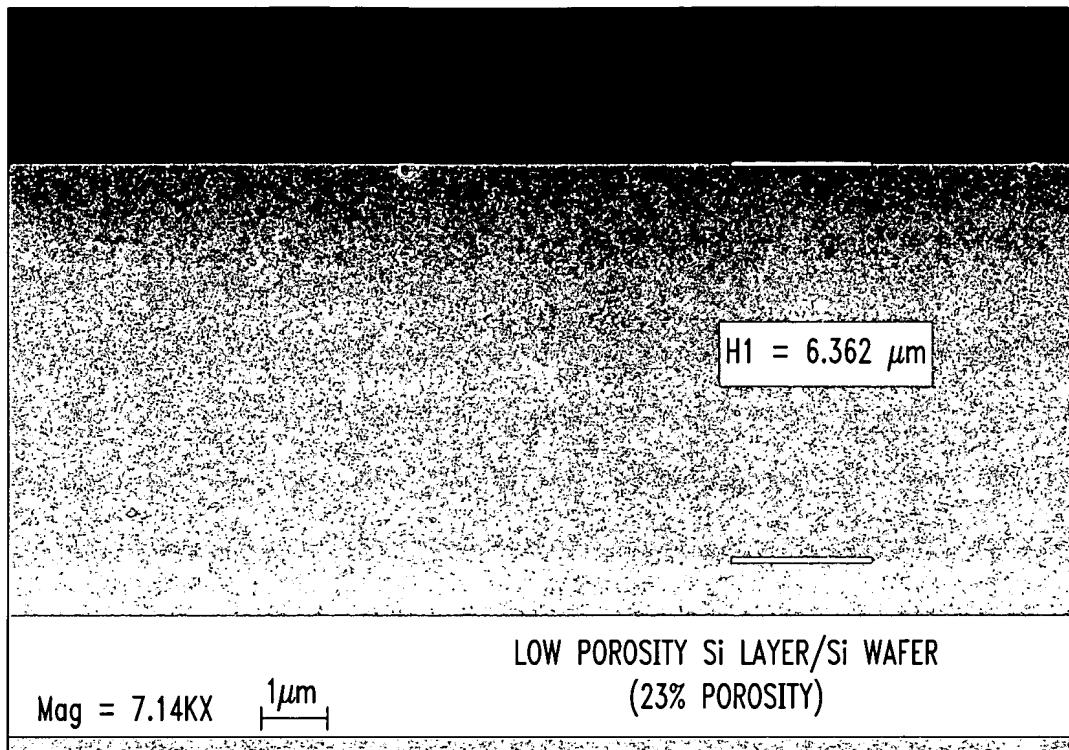


FIG. 1b

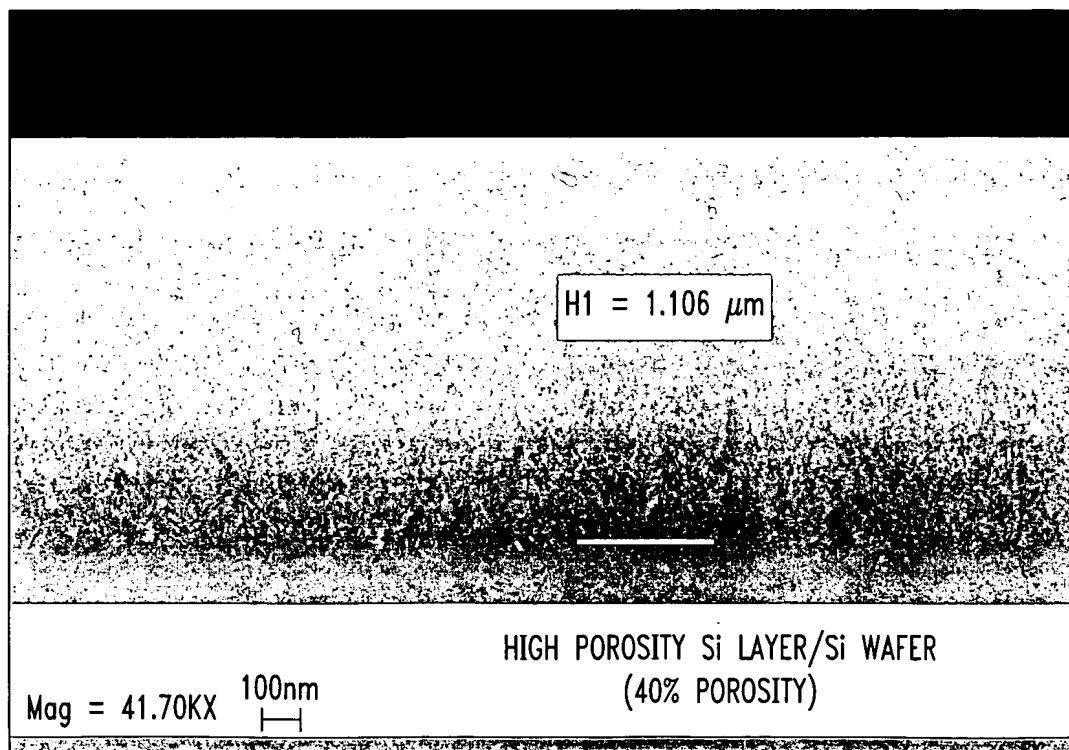


FIG. 1c

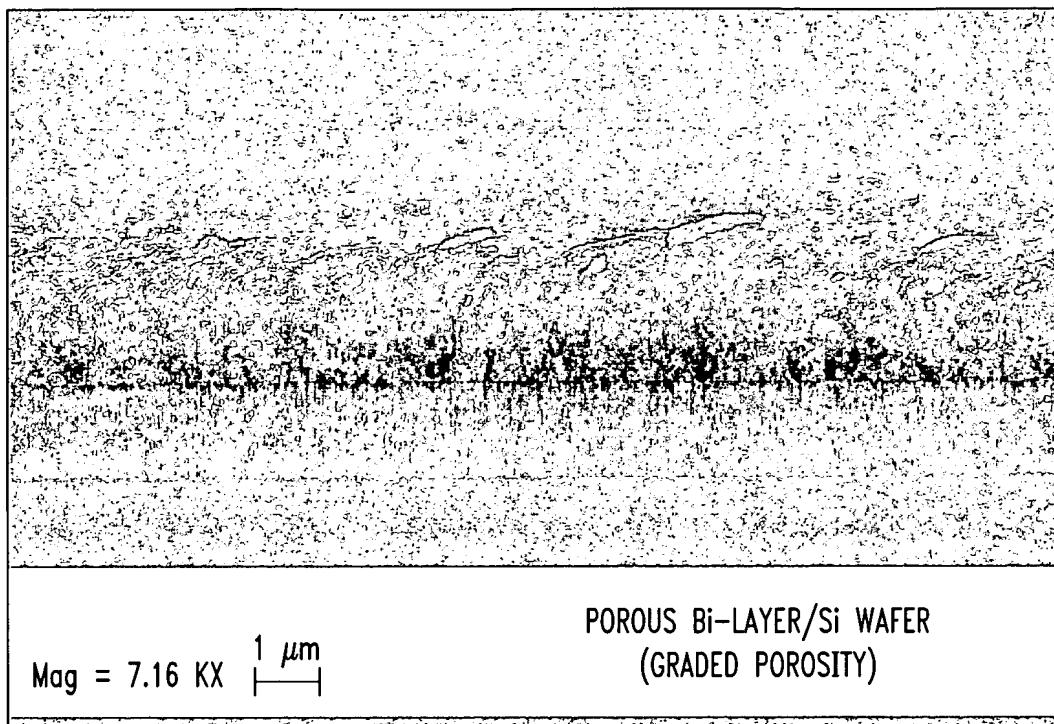


FIG. 2
SUBSTRATE BASED ON USE OF THE POROUS-SI LAYER AND
SUBSEQUENT REGROWTH OF epi-Si LAYER TO CREATE SOI WAFERS

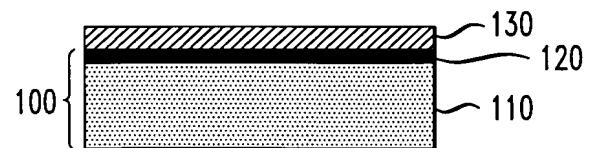


FIG. 3

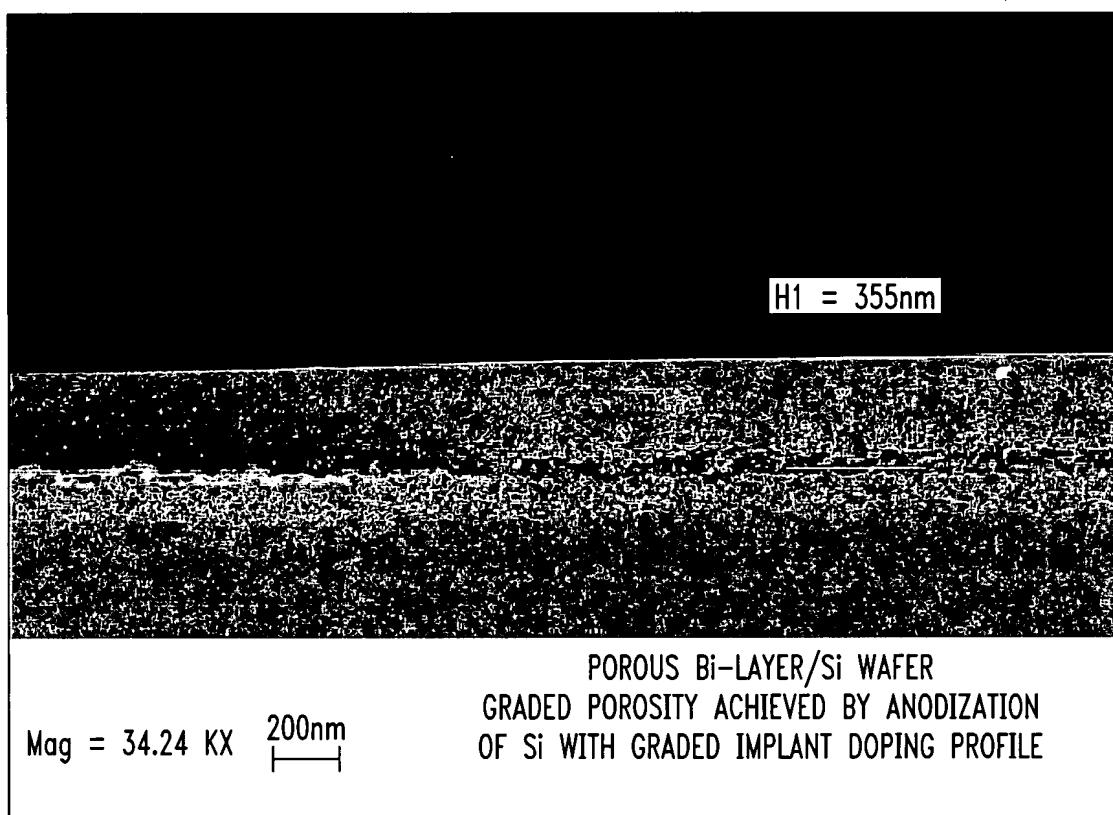


FIG. 4

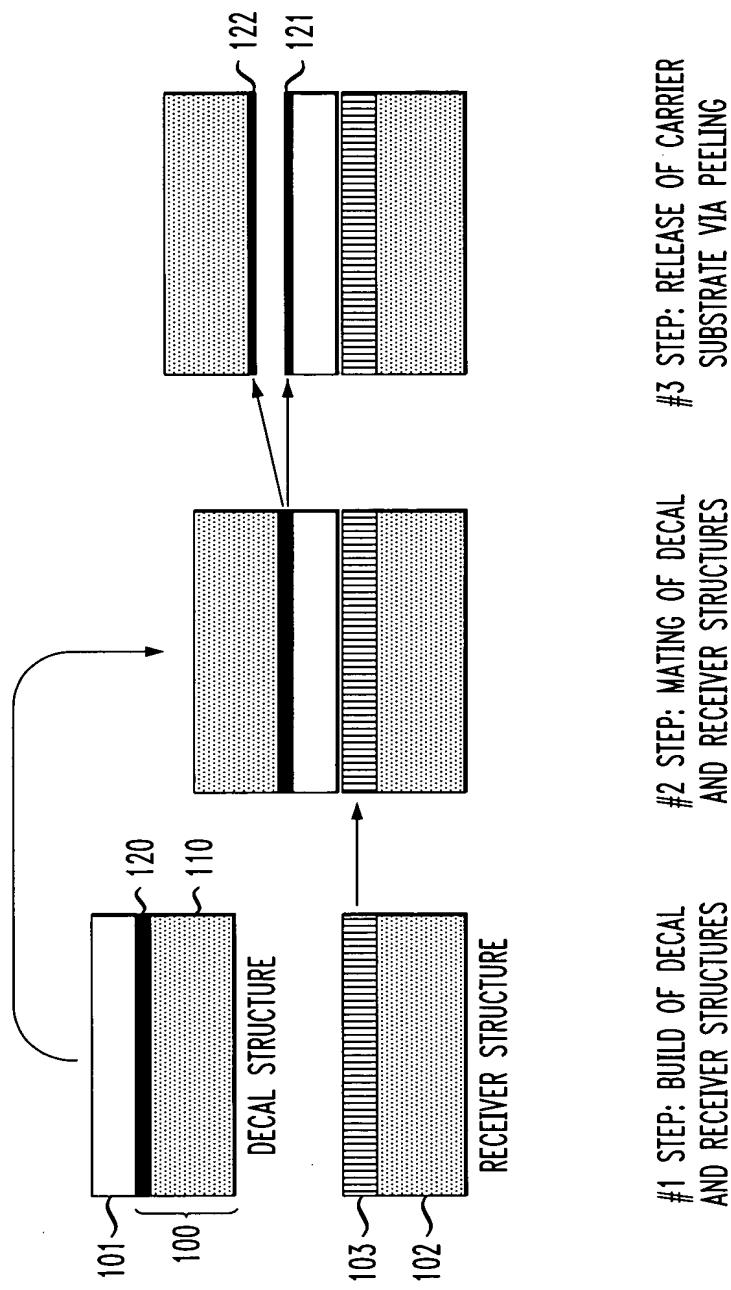


FIG. 5

